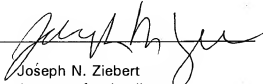


The Examiner is invited to contact the undersigned by telephone if it is felt that a telephone interview would advance the prosecution of the present application.

Respectfully submitted,

Date 3-29-02

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By 
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Version with Markings to Show Changes Made

In the Specification

Please replace the paragraph on page 7, lines 1 through 10 with the following paragraph:

With reference to FIGURE 2, computer system 30 can be embodied as a workstation or a personal computer. Computer system 30 can include a processor or computer [32] 40, an internal database [34] 44, a user interface 36, a media storage unit 38, and an external database 42. Computer [32] 40 can be a workstation or personal computer (PC) capable of providing a control signal (video signal, SVGA signal, television signal, etc.) to mask 20. Computer [32] 40 can receive commands from a user via interface 36. Interface 36 can include a keyboard, a display screen, a touch screen, a mouse, a trackball or other devices for displaying and receiving commands.

Please replace the paragraph on page 7, lines 11 through 20 with the following paragraph:

Computer system 30 can generate the control signal indicative of the image to be transferred to wafer 12. The control signal is generated based upon commands received from interface 36, and from data stored in database [34] 44, media storage unit 38 or database 42. Database [34] 44, unit 38, and database 42 can store representations of graphical images associated with IC structures, such as, transistors, vias, capacitors, pads, conductive lines, etc. Further, databases [34] 44, 42 and unit 38 can store the images for a number of layers to be formed on wafer 12. For example, the layout for metal layers (metal 1, metal 2, metal 3, etc.) can be stored in system 30.

Please replace the paragraph beginning on page 7, line 26 through page 8, line 2 with the following paragraph:

System 10 can provide ASIC-type functionality by selecting parts from database [34] 44, media storage unit 38, or database 42 in accordance with a program to

provide images on wafer 12. For example, a software program selecting transistors, diodes and their interconnections can be executed by computer [32] 40 to cause mask 20 to provide the appropriate structures on wafer 12.

Please replace the paragraph on page 8, lines 3 through 7 with the following paragraph:

The individual images for the individual parts can be stored in database [34] 44, media storage unit 38 or database 42. In this way, computer [32] 40 only operates a minimal software program describing the integrated circuit (IC). Images for individual components are retrieved from unit 38 or database 42 when needed.

Please replace the paragraph on page 8, lines 3 through 7 with the following paragraph:

Database [34] 44, media storage unit 38 and database 42 can be updated periodically to provide structures for particular processes, technologies, new structures, etc. In this way, updates do not require reformation of fixed masks for revision of the program executed by computer [12] 40 to generate the image on mask 20.

Please replace the paragraph on page 10, lines 21 through 30 with the following paragraph:

As shown in FIGURE 6, image 150 is provided for conductive lines on a metal layer provided on wafer 12. Mask 20 is most usable in situations where resolution associated with image 150 is not extremely demanding. In another area, mask 20 can be utilized to provide large pads for contacts and large power and ground planes for the integrated circuits on wafer [20] 12. In this way, the same mask 20 could be utilized for a variety of chips even though the contact, pad, ground and power plane images are different. Mask 20 would be continued to image the appropriate conductive plane, power plane and ground plane image. Image 150 is shown as an example only.